Search Notes



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10/797,614 Examiner

Mark A. X Radtke

Applicant(s)/Patent unde Reexamination

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	SEARCHED						
Class	Subclass	Date	Examiner				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)							
	DATE	EXMR					
Searched EAST	11/26/2006	MAXR					
Searched Google Scholar, ACM, IEEE	11/26/2006	MAXR					
PALM Inventor Name Search	11/26/2006	MAXR					
Double patenting search	11/26/2006	MAXR					
Consulted Primary Examiner Sam Rimell regarding allowable subject matter	11/29/2006	MAXR					
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